

Claims

1. A probe comprising:
 - (a) a substantially rigid support; and
 - (b) a plurality of contact fingers supported by and extending from said support, wherein said contact fingers are arranged as a unity assembly such that said plurality of contact fingers are maintained in a predetermined alignment when attached to said support.
2. The probe of claim 1 wherein a plurality of said contact fingers extend in a radially outward direction from said support.
3. The probe of claim 2 wherein the arrangement of said contact fingers match the geometry of a contacting pads on a device under test.
4. The probe of claim 1 wherein said support includes a resistor-capacitor network interconnected to said contact fingers.
5. The probe of claim 1 wherein said support is a planar circuit board.
6. The probe of claim 1 wherein said unitary assembly includes a tab proximate the ends of said plurality of contact fingers that maintains said contact fingers in said predetermined alignment.
7. The probe of claim 6 wherein said tab is removed prior to probing with said contact fingers.

8. The probe of claim 1 wherein said rigid support includes a respective trace for each of said contact fingers.
9. The probe of claim 8 wherein said respective traces are electrically interconnected to a connector suitable to interconnect to test equipment.
10. The probe of claim 7 wherein said removal of said tab leaves the ends of each of said plurality of contact fingers in a predetermined position.
11. The probe of claim 1 wherein said plurality of contact fingers is greater than three.
12. A method of assembling a probe comprising:
 - (a) providing a substantially rigid support;
 - (b) providing a unitary assembly including a plurality of contact fingers, such that said plurality of contact fingers are maintained in a predetermined alignment; and
 - (c) attaching said plurality of contact fingers to said support.
13. The method of claim 12 wherein a plurality of said contact fingers extend in a radially outward direction from said support.
14. The method of claim 13 wherein the arrangement of said contact fingers match the geometry of a contacting pads on a device under test.

15. The method of claim 12 wherein said support includes a resistor-capacitor network interconnected to said contact fingers.
16. The method of claim 12 wherein said support is a planar circuit board.
17. The method of claim 12 wherein said unitary assembly includes a tab proximate the ends of said plurality of contact fingers that maintains said contact fingers in said predetermined alignment.
18. The method of claim 17 wherein said tab is removed prior to probing with said contact fingers.
19. The method of claim 12 wherein said rigid support includes a respective trace for each of said contact fingers.
20. The method of claim 19 wherein said respective traces are electrically interconnected to a connector suitable to interconnect to test equipment.
21. The method of claim 18 wherein said removal of said tab leaves the ends of each of said plurality of contact fingers in a predetermined position.
22. The method of claim 12 wherein said plurality of contact fingers is greater than three.